Tailoring design to human needs is an art—and the chip on our cover is one example of technology filling the need for speed. For more details, see page 92.

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Volume 3 Number 1 (ISSN 0740-7475)

CONFERENCES

International Test Conference 1985:
Keynote Address 82
Experiences in VLSI Testing 83
Integration of Design and Test 83
Test Speeds Design 84
David and Fat-Cat Goliath 84
The 1985 ATE Slump 84
Built-In Self-Test 86
Third European Workshop on DFT 86
Seventh International Symposium on CHDL 87

DEPARTMENTS

D&T Scene 6
New Products—Test 88
New Products—Design 91
Calendar 93
Call for Papers 94
Education 94
Book Review 95
Change of Address Form 96
Reader Service Cards 96A

Coming in April: Workstations

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